Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/649,625	SEKI, YUICHI	
Examiner	**Art Unit**	
Jim Vannucci	2828	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
wafer lot, laser chips	11/8/2005	JV